General Description of SEM Sample Stub Adapters

The SEM stub adapters enable the use of different types of sample stubs or mounts in your SEM. Advantages of the cost-effective and practical SEM stub adapters are:

- sample mounting independent of SEM platform
- save time with no need to re-mount samples
- use calibration and resolution standards mounted on different stubs
- no need to risk sample integrity
- enables collaborative investigation of samples

There are basically 5 common types of SEM sample stubs:

- Standard pin stubs with standard 9.5mm long pin used on FEI, Philips, Tescan, Phenom, Aspex, RJ Lee, Cambridge Instruments, Leica, CamScan, ETEC and Novascan SEMs and SEM/FIB systems
- Zeiss pin stubs with short 6mm pin for Zeiss and LEO SEMs, CrossBeams and SEM/FIB systems
- Plain cylinder stubs for JEOL SEMs and SEM/FIB systems
- Hitachi cylinder stubs with M4 thread in the base for Hitachi SEMs and FIBs
- Plain cylinder stubs for ISI, ABT, Topcon SEMs

For each of the above type mentioned SEM stubs we offer SEM stub adapters. The SEM stub adapters are essentially made with the base of one type of an SEM sample stub and a top compatible with another type of SEM sample stub. They are all constructed of vacuum grade aluminum. SEM stub adapters types are available as:

- Pin stub adapters for using other SEM stubs in pin type SEMs such as FEI, Philips, Tescan, Phenom, Aspex, Cambridge Instruments, Leica, etc. These can be used in Amray systems as well.
- Short pin stub adapters for using other SEM stubs in Zeiss and LEO SEMs
- JEOL stub adapters for using other pin stubs and Hitachi stubs in JEOL SEMs
- Hitachi M4 stub adapters for using pin stubs and JEOL stubs in Hitachi SEMs
- Other SEM stub adapters for less common SEMs such as ISI/ABT/Topcon and Agilent/Keysight

For labs with multiple SEMs or for those who regularly use different brands of SEMs, we offer the versatile universal SEM stub adapter set. This set includes pin stub adapters, JEOL stub adapters (up to 25mm) and Hitachi stub adapters, all both ways.